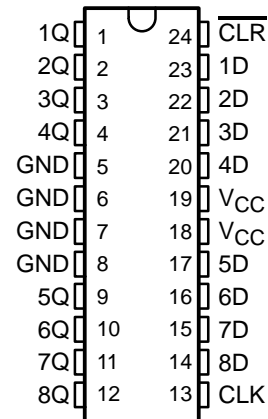


# 74AC11273 OCTAL D-TYPE FLIP-FLOP WITH CLEAR

SCAS497 – D3442, MARCH 1990 – REVISED APRIL 1993

- **Applications Include:**  
Buffer/Storage Registers  
Shift Registers  
Pattern Generators
- **Flow-Through Architecture to Optimize PCB Layout**
- **Multiple Center-Pin  $V_{CC}$  and GND Configurations to Minimize High-Speed Switching Noise**
- **EPIC™ (Enhanced-Performance Implanted CMOS) 1- $\mu$ m Process**
- **500-mA Typical Latch-Up Immunity at 125°C**
- **Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs**

**DW OR NT PACKAGE  
(TOP VIEW)**



## description

These positive-edge-triggered flip-flops implement D-type flip-flop logic with a direct clear input.

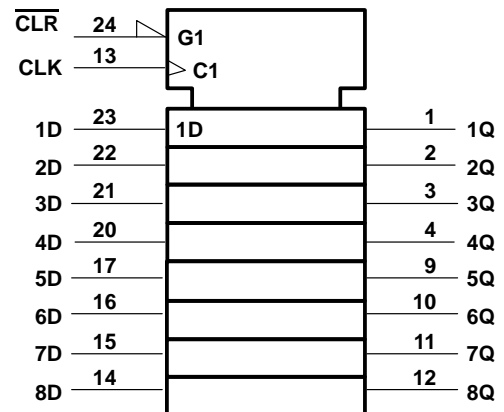
Data at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output.

The 74AC11273 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

**FUNCTION TABLE**

INPUTS			OUTPUT
CLR	CLK	D	Q
L	X	X	L
H	$\uparrow$	H	H
H	$\uparrow$	L	L
H	L	X	$Q_0$

**logic symbol†**



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



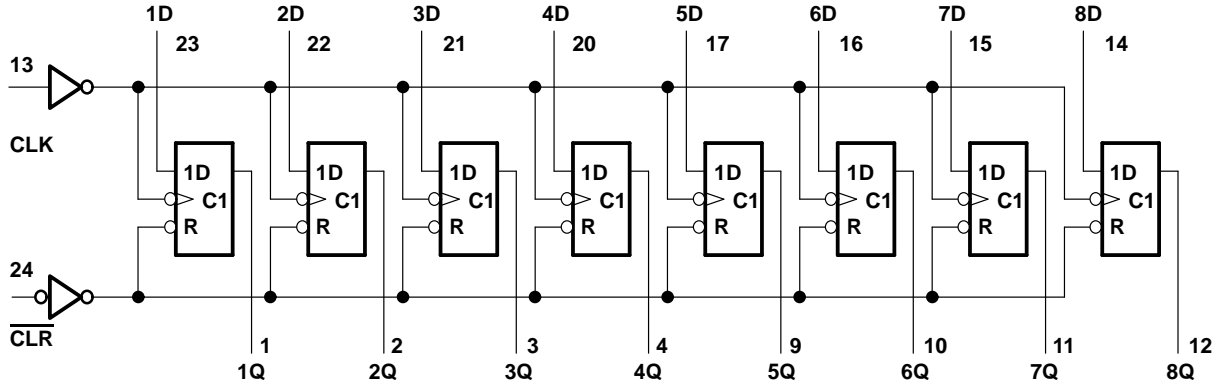
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## logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$ .....	-0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1) .....	-0.5 V to $V_{CC} + 0.5$ V
Output voltage range, $V_O$ (see Note 1) .....	-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) .....	$\pm 20$ mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ) .....	$\pm 50$ mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ ) .....	$\pm 50$ mA
Continuous current through $V_{CC}$ or GND .....	$\pm 200$ mA
Storage temperature range .....	-65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## recommended operating conditions

		MIN	NOM	MAX	UNIT
$V_{CC}$	Supply voltage	3	5	5.5	V
$V_{IH}$	High-level input voltage	$V_{CC} = 3$ V	2.1		V
		$V_{CC} = 4.5$ V	3.15		
		$V_{CC} = 5.5$ V	3.85		
$V_{IL}$	Low-level input voltage	$V_{CC} = 3$ V		0.9	V
		$V_{CC} = 4.5$ V		1.35	
		$V_{CC} = 5.5$ V		1.65	
$V_I$	Input voltage	0		$V_{CC}$	V
$V_O$	Output voltage	0		$V_{CC}$	V
$I_{OH}$	High-level output current	$V_{CC} = 3$ V		-4	mA
		$V_{CC} = 4.5$ V		-24	
		$V_{CC} = 5.5$ V		-24	
$I_{OL}$	Low-level output current	$V_{CC} = 3$ V		12	mA
		$V_{CC} = 4.5$ V		24	
		$V_{CC} = 5.5$ V		24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
$T_A$	Operating free-air temperature	-40		85	°C



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**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V <sub>OH</sub>	I <sub>OH</sub> = - 50 μA	3 V	2.9			2.9		V
		4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
	I <sub>OH</sub> = - 4 mA	3 V	2.58			2.48		
		4.5 V	3.94			3.8		
	I <sub>OH</sub> = - 24 mA	4.5 V	3.94			3.8		
		5.5 V	4.94			4.8		
I <sub>OH</sub> = - 50 mA <sup>†</sup>	5.5 V							
I <sub>OH</sub> = - 75 mA <sup>†</sup>	5.5 V				3.85			
V <sub>OL</sub>	I <sub>OL</sub> = 50 μA	3 V				0.1		V
		4.5 V				0.1		
		5.5 V				0.1		
	I <sub>OL</sub> = 12 mA	3 V				0.36		
		4.5 V				0.36		
	I <sub>OL</sub> = 24 mA	4.5 V				0.36		
		5.5 V				0.36		
I <sub>OL</sub> = 50 mA <sup>†</sup>	5.5 V							
I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V				1.65			
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V				± 0.1		μA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	5.5 V				8		μA
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V				4		pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

**timing requirements over recommended operating free-air temperature range, V<sub>CC</sub> = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)**

		T <sub>A</sub> = 25°C		MIN	MAX	UNIT	
		MIN	MAX				
f <sub>clock</sub>	Clock frequency	0	55	0	55	MHz	
t <sub>w</sub>	Pulse duration	CLR low	6		6		ns
		CLK high or low	9.1		9.1		
t <sub>su</sub>	Setup time before CLK <sup>↑</sup>	Data	7.5		7.5		ns
		CLR inactive	6		6		
t <sub>h</sub>	Hold time, data after CLK <sup>↑</sup>	0		0		ns	

**timing requirements over recommended operating free-air temperature range, V<sub>CC</sub> = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)**

		T <sub>A</sub> = 25°C		MIN	MAX	UNIT	
		MIN	MAX				
f <sub>clock</sub>	Clock frequency	0	80	0	80	MHz	
t <sub>w</sub>	Pulse duration	CLR low	5		5		ns
		CLK high or low	6.3		6.3		
t <sub>su</sub>	Setup time before CLK <sup>↑</sup>	Data	5		5		ns
		CLR inactive	4.5		4.5		
t <sub>h</sub>	Hold time, data after CLK <sup>↑</sup>	0		0		ns	

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switching characteristics over recommended operating free-air temperature range,  
 $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$T_A = 25^\circ\text{C}$			MIN	MAX	UNIT
			MIN	TYP	MAX			
$f_{\text{max}}$			55			55		MHz
$t_{\text{PHL}}$	$\overline{\text{CLR}}$	Any Q	5.2	14.3	16.5	5.2	18.4	ns
$t_{\text{PLH}}$	CLK	Any Q	4.2	12.1	14.3	4.2	16.5	ns
$t_{\text{PHL}}$			5.5	14.5	16.7	5.5	18.6	

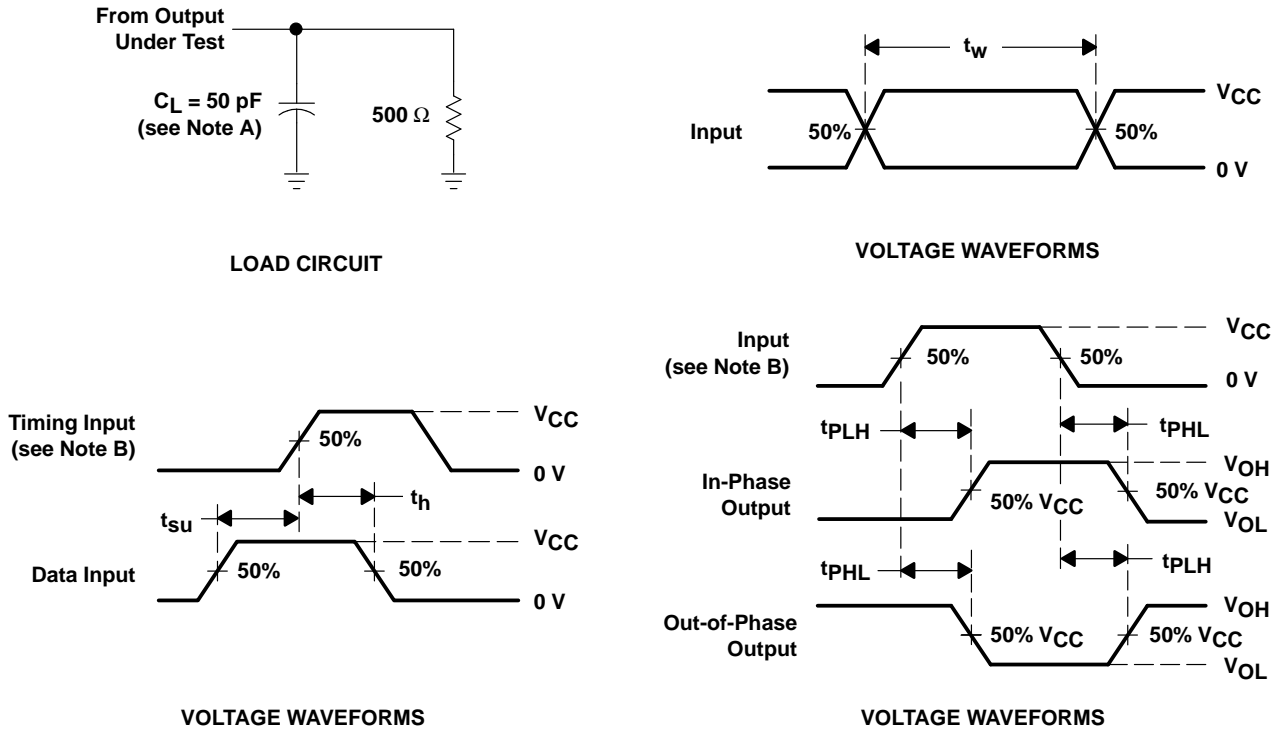
switching characteristics over recommended operating free-air temperature range,  
 $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$T_A = 25^\circ\text{C}$			MIN	MAX	UNIT
			MIN	TYP	MAX			
$f_{\text{max}}$			80			80		MHz
$t_{\text{PHL}}$	$\overline{\text{CLR}}$	Any Q	4.3	9.2	10.9	4.3	12.3	ns
$t_{\text{PLH}}$	CLK	Any Q	3.5	7.7	9.3	3.5	10.7	ns
$t_{\text{PHL}}$			4.5	9.3	11	4.5	12.4	

operating characteristics,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
$C_{\text{pd}}$ Power dissipation capacitance	$C_L = 50\text{ pF}$ , $f = 1\text{ MHz}$	80	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .  
 C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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